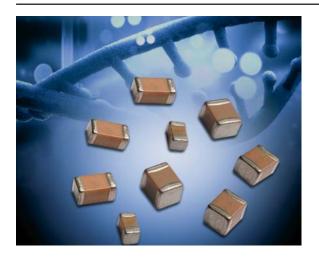
General Specifications



The AVX MM series is a multi-layer ceramic capacitor designed for use in medical applications other than implantable/life support. These components have the design & change control expected for medical devices and also offer enhanced LAT including reliability testing and 100% inspection.

APPLICATIONS

Implantable, Non-Life Supporting Medical Devices

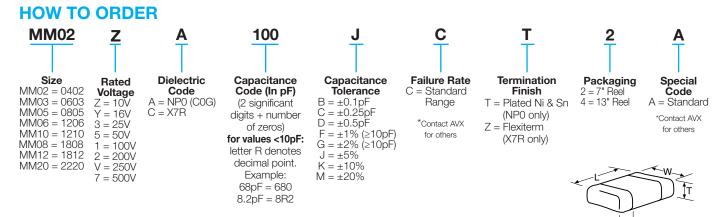
• e.g. implanted temporary cardiac monitor, insulin pumps

External, Life Supporting Medical Devices

• e.g. heart pump external controller

External Devices

• e.g. patient monitoring, diagnostic equipment



COMMERCIAL VS MM SERIES PROCESS COMPARISON

	Commercial	MM Series						
Administrative	Standard part numbers; no restriction on who purchases these parts	Specific series part number, used to control supply of product						
Design	Minimum ceramic thickness of 0.020" on all X7R product	Minimum ceramic thickness of 0.029" (0.74mm)						
Dicing	Side & end margins = 0.003" min	Side & end margins = 0.004" min Cover layers = 0.003" min						
Lot Qualification Destructive Physical Analysis (DPA)	As per EIA RS469	Increased sample plan – stricter criteria						
Visual/Cosmetic Quality	Standard process and inspection	100% inspection						
Application Robustness	Standard sampling for accelerated wave solder on X7R dielectrics	Increased sampling for accelerated wave solder on X7R and NP0 followed by lot by lot reliability testing						
Design/Change Control	Required to inform customer of changes in: • form • fit • function	AVX will qualify and notify customers before making any change to the following materials or processes: • Dielectric formulation, type, or supplier • Metal formulation, type, or supplier • Termination material formulation, type, or supplier • Manufacturing equipment type • Quality testing regime including sample size and accept/ reject criteria						

NP0 (C0G) - Specifications & Test Methods

	ter/Test	NP0 Specification Limits	Measuring Conditions Temperature Cycle Chamber										
	perature Range	-55°C to +125°C											
Capac	itance	Within specified tolerance	Freq.: 1.0 MHz ± 109										
(2	<30 pF: Q≥ 400+20 x Cap Value ≥30 pF: Q≥ 1000	1.0 kHz ± 10% for cap > 1000 pF Voltage: 1.0Vrms ± .2V										
Inculation	Resistance	100,000M Ω or 1000M Ω - μF,	Charge device with rated voltage for										
Ilisulation	nesistance	whichever is less	60 ± 5 secs @ roc										
Dielectric	: Strength	No breakdown or visual defects	Charge device with 300% of rated voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max) Note: Charge device with 150% of rated voltage for 500V devices.										
	Appearance	No defects	Deflectio	n: 2mm									
Resistance to	Capacitance Variation	±5% or ±.5 pF, whichever is greater	Test Time: 3	80 seconds 7 1mm/sec									
Flexure Stresses	Q	Meets Initial Values (As Above)	V										
	Insulation Resistance	≥ Initial Value x 0.3	90 r										
Solderability		≥ 95% of each terminal should be covered with fresh solder	Dip device in eutectic for 5.0 ± 0.										
	Appearance	No defects, <25% leaching of either end terminal											
	Capacitance Variation	≤ ±2.5% or ±.25 pF, whichever is greater	Dip device in eutectic solder at 260°C for 60 seconds. Store at room temperature for 24 ± 2 hours before measuring electrical properties.										
Resistance to Solder Heat	Q	Meets Initial Values (As Above)											
	Insulation Resistance	Meets Initial Values (As Above)		9									
	Dielectric Strength	Meets Initial Values (As Above)											
	Appearance	No visual defects	Step 1: -55°C ± 2°	30 ± 3 minutes									
	Capacitance Variation	≤ ±2.5% or ±.25 pF, whichever is greater	Step 2: Room Temp	≤ 3 minutes									
Thermal Shock	Q	Meets Initial Values (As Above)	Step 3: +125°C ± 2°	30 ± 3 minutes									
Gilook	Insulation Resistance	Meets Initial Values (As Above)	Step 4: Room Temp	≤ 3 minutes									
	Dielectric Strength	Meets Initial Values (As Above)	Repeat for 5 cycles and measure after 24 hours at room temperature										
	Appearance	No visual defects											
	Capacitance Variation	≤ ±3.0% or ± .3 pF, whichever is greater	Charge device with to										
Load Life	Q (C=Nominal Cap)	≥ 30 pF: Q≥ 350 ≥10 pF, <30 pF: Q≥ 275 +5C/2 <10 pF: Q≥ 200 +10C	test chamber set at 125°C ± 2°C for 1000 hours (+48, -0).										
	Insulation Resistance	≥ Initial Value x 0.3 (See Above)	Remove from test cha room temperatu	ire for 24 hours									
	Dielectric Strength	Meets Initial Values (As Above)	before me	easuring.									
	Appearance	No visual defects											
	Capacitance Variation	≤ ±5.0% or ± .5 pF, whichever is greater	Store in a test chamb										
Load Humidity	Q	≥ 30 pF: Q≥ 350 ≥10 pF, <30 pF: Q≥ 275 +5C/2 <10 pF: Q≥ 200 +10C	$85\% \pm 5\%$ relative hui (+48, -0) with rate	d voltage applied.									
	Insulation Resistance	≥ Initial Value x 0.3 (See Above)	Remove from cham room temperature	for 24 ± 2 hours									
	Dielectric Strength	Meets Initial Values (As Above)	before measuring.										

NP0/C0G Capacitance Range

PREFERRED SIZES ARE SHADED

SI	ZE			06	03			0805			1206											
	WVDC 0R5		16	25	50	100	16	25	50	100	16	25	50	100								
Cap 0.5																						
(pF) 1.0) 1F	30																				
1.2	1F	32																				
1.5	1F	35																				
1.8																						
2.2																						
2.7																						
3.3																						
3.9																						
4.7																						
5.6																						
6.8																						
8.2																						
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47																						
56																						
68																						
82																						
100																						
120																						
150																						
180																						
220																						
270																						
330																						
390																						
470																						
560																						
680																						
820																						
1000																						
1200																						
1500																						
	WVD	C	16	25	50	100	16	25	50	100	16	25	50	100								
SIZE				0603				0805			1206											

X7R Specifications and Test Methods

Parame	ter/Test	X7R Specification Limits	Measuring Conditions									
Operating Temp		-55°C to +125°C	Temperature C									
Capac Dissipation		Within specified tolerance ≤ 10% for ≥ 50V DC rating ≤ 12.5% for 25V DC rating ≤ 12.5% for 25V and 16V DC rating	Freq.: 1.0 k Voltage: 1.0									
Insulation I	Resistance	\leq 12.5% for \leq 10V DC rating 100,000MΩ or 1000MΩ - μ F, whichever is less	Charge device with 120 ± 5 secs @ roo									
Dielectric	Strength	No breakdown or visual defects	Charge device with 300 1-5 seconds, w/charge limited to 50	120 ± 5 secs @ room temp/humidity Charge device with 300% of rated voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max) Note: Charge device with 150% of rated								
	Derature Range itance Itance	No defects	Deflectio									
Resistance to	Capacitance	≤ ±12%	Test Time: 3									
Flexure Stresses	Dissipation	Meets Initial Values (As Above)	V	/ IIIIII/sec								
	Insulation	≥ Initial Value x 0.3	90 n	nm —								
Solder	rability	≥ 95% of each terminal should be covered with fresh solder	Dip device in eutection for 5.0 ± 0.									
		No defects, <25% leaching of either end terminal										
		≤ ±7.5%	Dip device in eutectic s	colder at 260°C for 60								
Resistance to		Meets Initial Values (As Above)	seconds. Store at room temperature for 24 ± 2 hours before measuring electrical properties.									
Solder Heat		Meets Initial Values (As Above)	Tiours before measuring	g electrical properties.								
		Meets Initial Values (As Above)										
		No visual defects	Step 1: -55°C ± 2°	30 ± 3 minutes								
	Capacitance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Capacitance Variation Dissipation Factor Insulation Resistance Dielectric	≤ ±7.5%	Step 2: Room Temp	≤ 3 minutes								
Thermal Shock		Meets Initial Values (As Above)	Step 3: +125°C ± 2°	30 ± 3 minutes								
SHOCK		Meets Initial Values (As Above)	Step 4: Room Temp	≤ 3 minutes								
	Appearance Capacitance Variation Dissipation Factor Insulation Resistance Variation Dissipation Factor Insulation Resistance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Capacitance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Capacitance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Capacitance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Capacitance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Capacitance Variation Dissipation Factor Insulation Factor Insulation Factor Insulation	Meets Initial Values (As Above)	Repeat for 5 cycles ar 24 ± 2 hours at room									
		No visual defects										
		≤ ±12.5%	Charge device with 1.5 test chamber set									
Load Life		≤ Initial Value x 2.0 (See Above)	for 1000 hou	urs (+48, -0)								
		≥ Initial Value x 0.3 (See Above)	Remove from test ch at room temperatur	re for 24 ± 2 hours								
		Meets Initial Values (As Above)	before me	easuring.								
	Appearance	No visual defects	Store in a test chamb	or oot at 9500 : 000/								
	Variation	≤ ±12.5%	85% ± 5% relative hur	midity for 1000 hours								
Load Humidity		≤ Initial Value x 2.0 (See Above)	(+48, -0) with rated Remove from cham									
	Resistance	≥ Initial Value x 0.3 (See Above)	room temperature	and humidity for								
		Meets Initial Values (As Above)	24 ± 2 hours be	iore measuring.								

X7R Capacitance Range

PREFERRED SIZES ARE SHADED

	SIZI	E		04	02			0	60	3					(080	5						12	06							12	210				-	1808	8		18	312	2	222	0	
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Cap	220	221																																								П			
pf	270	271				T																						ı											П	\neg	\Box	П	П		
	330	331																																											
	390	391				П																						П								Г	П		П	\neg	П		П		
	470	471				П																																		\neg	П		П		
	560	561				П																																		\neg	П		П		
	680	681																																											
	820	821																																											
	1000	102																																											
	1200	122																																											
	1500	152																																											
	1800	182																																											匚
	2200	222																																			\Box	\Box	ш			\sqcup		\perp	\perp
	2700	272				L																																			\square				L
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